

AOK065V65X2 650V @ SiC Silicon Carbide Power MOSFET

### **Features**

- Proprietary αSiC MOSFET technology
- · Low loss, fast switching speeds with low R<sub>G</sub>
- Optimized drive voltage (V<sub>GS</sub> =15V) for broad driver compatibility
- Robust body diode and low Qrr

## **Applications**

- Renewable
- IndustrialUPS
- EV Charger Solar Inverters
- SMPS
  - Motor Drives

# Product Summary

V <sub>DS</sub> @ T <sub>J, max</sub>	650V
I <sub>DM</sub>	85A
R <sub>DS(ON), typ</sub>	65mΩ
Q <sub>rr</sub>	104nC
E <sub>OSS</sub> @ 400V	11µJ
100% UIS Tested	



# Pin Configuration



Ordering Part Number	Ordering Part Number Package Type		Shipping Quantity	
AOK065V65X2	TO-247-3L	Tube	30/Tube	

### **Absolute Maximum Ratings**

 $(T_A = 25^{\circ}C, unless otherwise noted)$ 

Symbol		AOK065V65X2	Units		
V <sub>DS</sub>	Drain-Source Voltage		650	V	
V <sub>GS, MAX</sub>		Maximum	-8/+18	V	
V <sub>GS,OP,TRANS</sub>	Gate-Source Voltage	Max Transient <sup>(A)</sup>	-8/+20		
V <sub>GS,OP</sub>		Recommended Operating <sup>(B)</sup>	-5/+15		
1	Continuous Drain Current	$T_{C} = 25^{\circ}C$	40.3		
D		$T_{\rm C} = 100^{\circ}{\rm C}$	29.6	Α	
I <sub>DM</sub>	Pulsed Drain Current <sup>(C)</sup>		85		
E <sub>AS</sub>	Single Pulsed Avalanche Energy <sup>(D)</sup>		250	mJ	
P <sub>D</sub>	Power Dissipation <sup>(C)</sup>		187.5	W	
T <sub>J</sub> , T <sub>STG</sub>	Junction and Storage Temp	-55 to 175	°C		
TL	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds		300	°C	



#### **Thermal Characteristics**

Symbol	Parameter	AOK065V65X2	Units
R <sub>0JA</sub>	Maximum Junction-to-Ambient (E,F)	40	°C/W
R <sub>θJC</sub>	Maximum Junction-to-Case (G)	0.8	°C/W

#### **Electrical Characteristics**

 $(T_A = 25^{\circ}C, unless otherwise noted)$ 

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC							
V	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C					V
V <sub>(BR)DSS</sub>	Dialii-Source Breakdowii voltage	I <sub>D</sub> =250µA, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C			650		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V				1	μA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =+15/-5V				±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =10mA		1.8	2.8	3.5	V
			T <sub>J</sub> = 25°C		65	85	
R <sub>DS(ON)</sub>		V <sub>GS</sub> =15V, I <sub>D</sub> =10A	TJ= 150°C		90		mΩ
9 <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =20V, I <sub>D</sub> =20V			12		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =10A,V <sub>GS</sub> =-5V			4.1	5	V
DYNAMIC						<u> </u>	
C <sub>iss</sub>	Input Capacitance				1762		pF
C <sub>oss</sub>	Output Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V, f=1MHz			297		pF
C	Reverse Transfer Capacitance				12		pF
E <sub>oss</sub>	Coss Stored Energy				30		μJ
R <sub>G</sub>	Gate Resistance	f=1MHz			2.5		Ω
SWITCHIN	G						
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> =-5/+15V, V <sub>DS</sub> =400V, I <sub>D</sub> =20A			58.8		nC
Q <sub>gs</sub>	Gate Source Charge				24.6		nC
Q <sub>gd</sub>	Gate Drain Charge				19.7		nC
t <sub>d(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> =-5V/+15V, V <sub>DS</sub> =400V,			10.4		ns
t <sub>r</sub>	Turn-On Rise Time				25.5		ns
t <sub>d(off)</sub>	Turn-Off DelayTime		,		12.4		ns
t <sub>f</sub>	Turn-Off Fall Time	I <sub>D</sub> =20A, R <sub>G</sub> =2.5Ω			3.9		ns
E <sub>on</sub>	Turn-On Energy	La = 120µH			131.5		μJ
E <sub>off</sub>	Turn-Off Energy	FWD: AOK065V65X2			8.9		μJ
E <sub>tot</sub>	Total Switching Energy	1			140.4		μJ
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =13.2A,dl/dt=1200A/us, V <sub>DS</sub> =400V=33ns			33		ns
I <sub>rm</sub>	Peak Reverse Recovery Current	I <sub>F</sub> =13.2A,dl/dt=750A/us, V <sub>DS</sub> =400V=6.4A			6.4		Α
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =13.2A,dl/dt=750A/us, V <sub>DS</sub> =400V=104nC			104		nC

Notes:

A. < 1% duty cycle, f >1Hz

B. Device can be operated at Ves=0/15V. Actual operating VGS will depend on application specifics such as parasitic inductance and dV/dt but should not c. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =175°C, using junction-to-case F. The  $R_{\mbox{\tiny BJA}}$  is the sum of the thermal impedance from junction to case  $R_{\mbox{\tiny BJC}}$  and case to ambient.

G. The value of  $R_{BJC}$  is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(MAX)}$ =175°C. H. The static characteristics in Figures 1 to 8 are obtained using <300ms H. The static bilateristics in Figures Field are obtained using "connection pulses, duty cycle 0.5% max. I. These curves are based on  $R_{\text{BJC}}$  which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(MAX)}$  =175°C. The SOA curve provides a single pulse rating.

thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used. D. L=5mH, I<sub>AS</sub>=10A, R<sub>G</sub>=25Ω, Starting T<sub>J</sub>=25°C. E. The value of R<sub>8JA</sub> is measured with the device in a still air environment with T<sub>A</sub>=25°C.

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### **Typical Electrical and Thermal Characteristics**

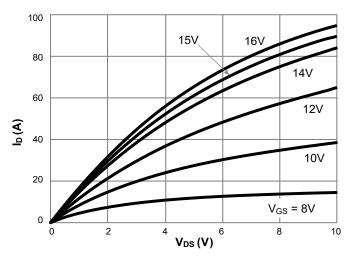


Figure 1. On-Region Characteristics T<sub>J</sub> = 25°C

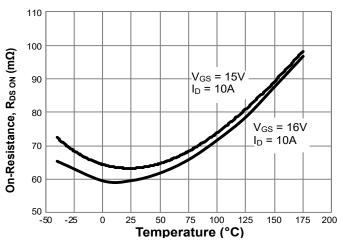
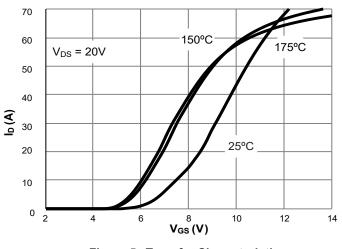
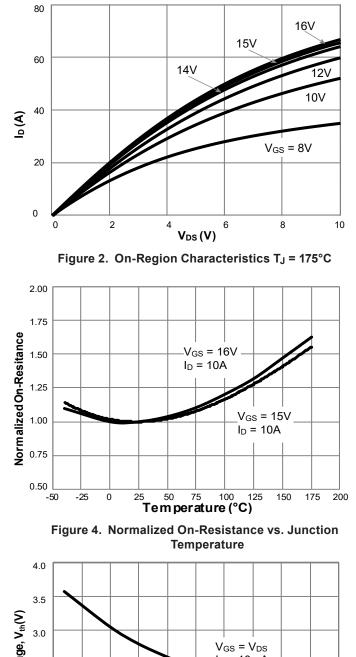
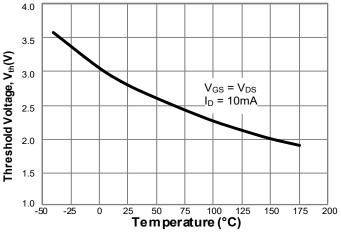


Figure 3. On-Resistance vs. Junction Temperature













## **Typical Electrical and Thermal Characteristics**

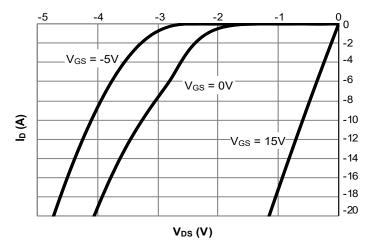


Figure 7. Body-Diode Characteristics at 25°C

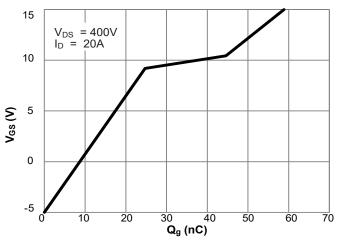
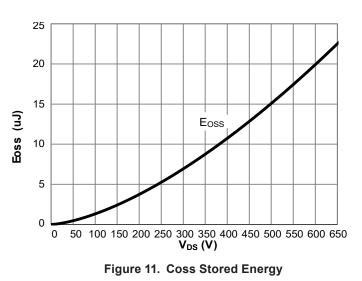


Figure 9. Gate-Charge Characteristics



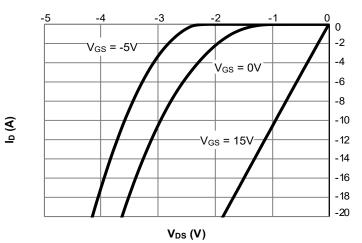


Figure 8. Body-Diode Characteristics at 175°C

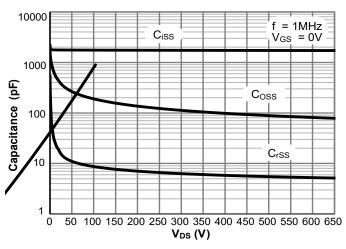
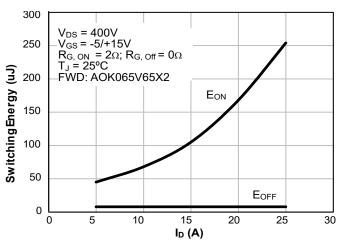
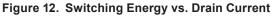


Figure 10. Capacitance Characteristics





### **Typical Electrical and Thermal Characteristics**

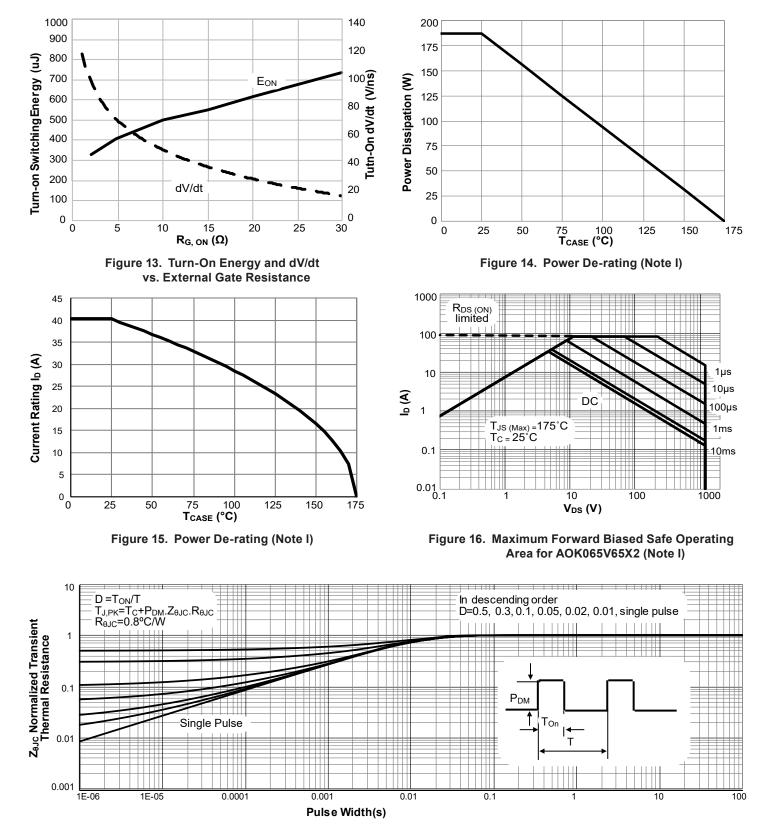
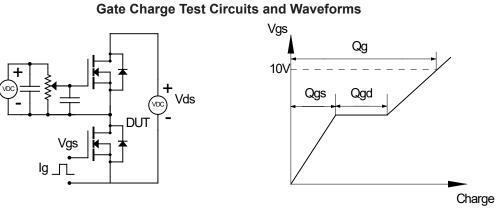


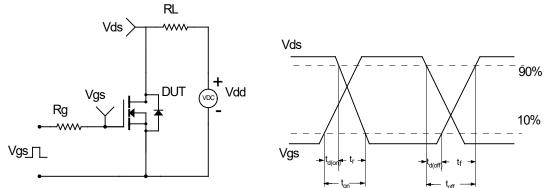
Figure 17. Normalized Maximum Transient Thermal Impedance for AOK065V65X2 (Note I)



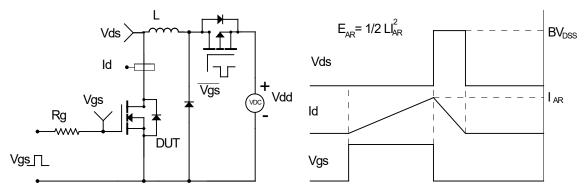
### **Test Circuits and Waveforms**



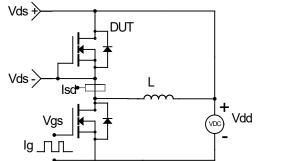
#### **Resistive Switching Test Circuit and Waveforms**

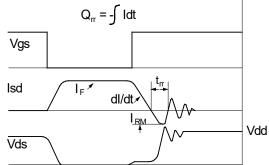


#### Unclamped Inductive Switching (UIS) Test Circuit and Waveforms



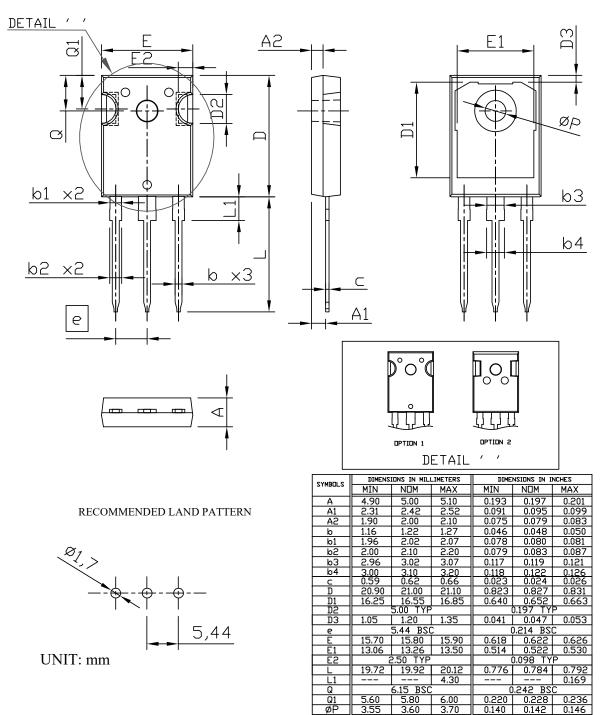
#### **Gate Charge Test Circuits and Waveforms**







### Package Dimensions, TO247-3L



#### NOTE

1. PAKCAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.

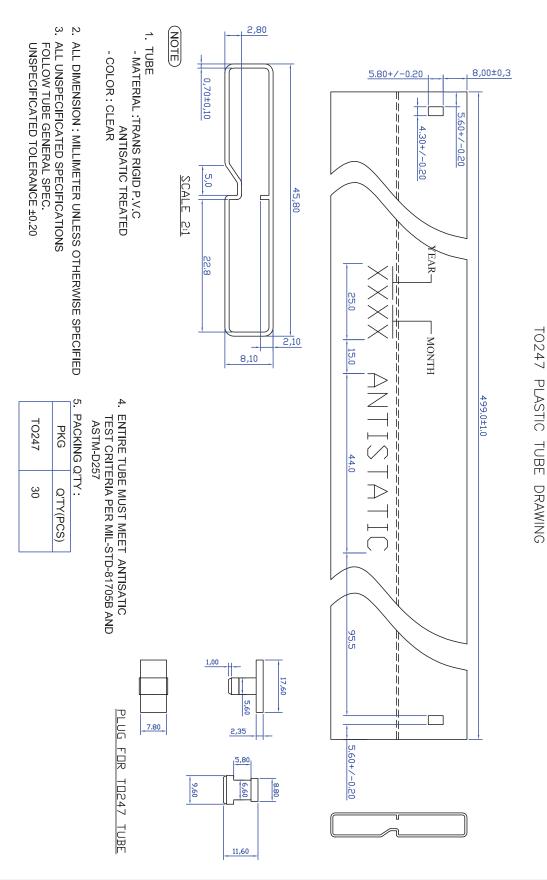
MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.

2. CONTROLLING DIMENSION IS MILLIMETER.

CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



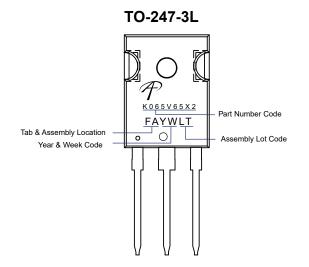
### Tape and Reel Dimensions, TO247-3L



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### **Part Marking**



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